INTERFERENCE

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L17	1	(((test$4 near10 (IC or (integrated adj circuit))) and ((partition$4 or divid$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack$5 and conduct$3 and I/O and pad).CLM.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:48

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	7918	(test$4 same (IC or (integrated adj circuit))) and pattern and chip and pack$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:58
L2	2862	(test$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L3	9	(test$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack$5 and pad and (fan-out or fan adj2 out) and "716"/$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:57
L4	116	(test$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack$5 and pad and (fan-out or fan adj2 out)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L5	74	(test$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L6	3	(test$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct$4 and partition$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L7	64	(test$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L8	64	(test$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct$4 and function$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50

L9	20	(test$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct$4 and function$3 and (partition$3 or divid$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L10	96	(test$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack$5 and pad and (fan-out or fan adj2 out) and ("716"/$.ccls. or "324"/$.ccls. or "257"/$.ccls.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L11	820	(test$4 near10 (IC or (integrated adj circuit))) and ((partition$4 or divid$3) same (IC or (integrated adj circuit))) and pattern and chip and pack$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:12
L12	268	(test$4 near10 (IC or (integrated adj circuit))) and ((partition$4 or divid$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:13
L13	9	(test$4 near10 (IC or (integrated adj circuit))) and ((partition$4 or divid$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack$5 and (fan-out or fan adj out) and (I/O or (input same output) same pad)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:18
L14	14	(test$4 near10 (IC or (integrated adj circuit))) and ((partition$4 or divid$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack$5 and (fan-out or fan adj out)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:19
L15	63	(test$4 near10 (IC or (integrated adj circuit))) and ((partition$4 or divid$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack$5 and conduct$3 and (I/O same pad)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:20
L16	1	(test$4 near10 (IC or (integrated adj circuit))) and ((partition$4 or divid$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack$5 and conduct$3 and (I/O same pad) and "716"/$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:47

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Proceedings of the IEEE
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Volume 33, Issue 11, Nov. 1998 Page(s):1741 - 1751
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    <and> pitch <and> pattern <and> I/O

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